

# 2SA2201

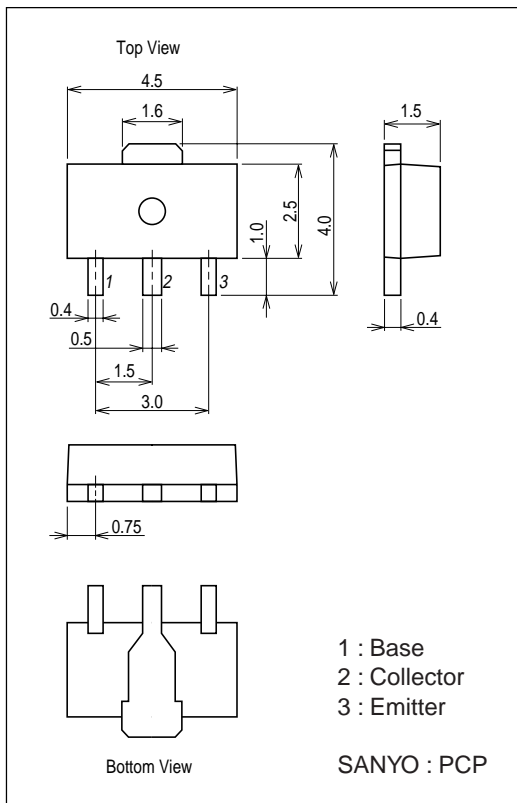
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Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	
Collector-to-Emitter Saturation Voltage	$V_{CE(sat)}$	$I_C = -1A, I_B = -100mA$		-90	-180	mV
Base-to-Emitter Saturation Voltage	$V_{BE(sat)}$	$I_C = -1A, I_B = -100mA$		-0.85	-1.2	V
Collector-to-Base Breakdown Voltage	$V_{(BR)CBO}$	$I_C = -10\mu A, I_E = 0A$	-80			V
Collector-to-Emitter Breakdown Voltage	$V_{(BR)CES}$	$I_C = -100\mu A, R_{BE} = 0\Omega$	-80			V
Collector-to-Emitter Breakdown Voltage	$V_{(BR)CEO}$	$I_C = -1mA, R_{BE} = \infty$	-80			V
Emitter-to-Base Breakdown Voltage	$V_{(BR)EBO}$	$I_E = -10\mu A, I_C = 0A$	-7			V
Turn-ON Time	$t_{on}$	See specified Test Circuit.		40		ns
Storage Time	$t_{stg}$	See specified Test Circuit.		500		ns
Fall Time	$t_f$	See specified Test Circuit.		28		ns

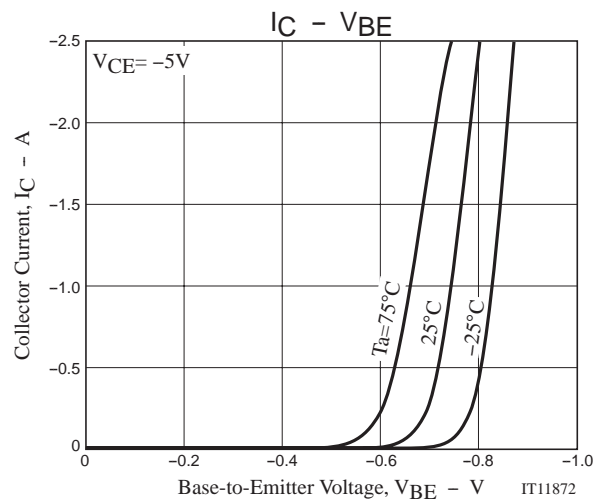
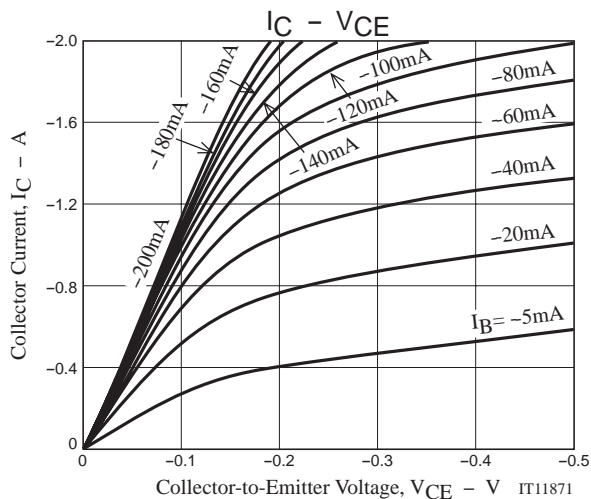
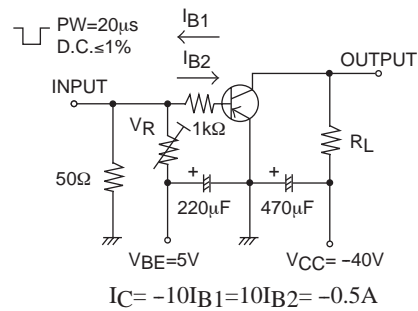
## Package Dimensions

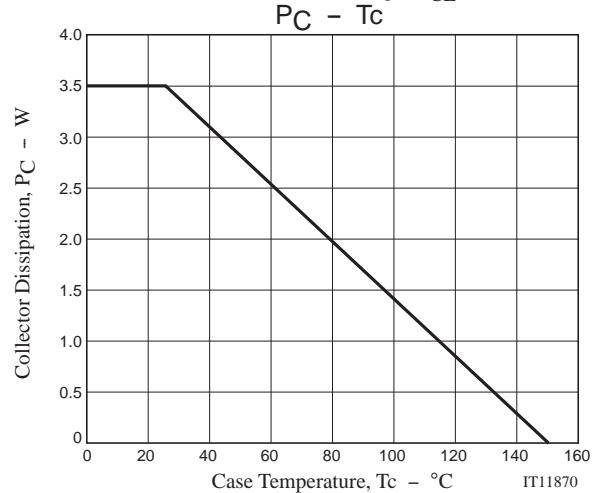
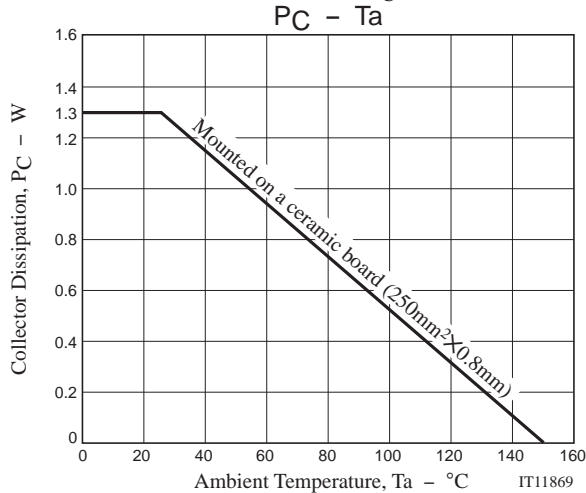
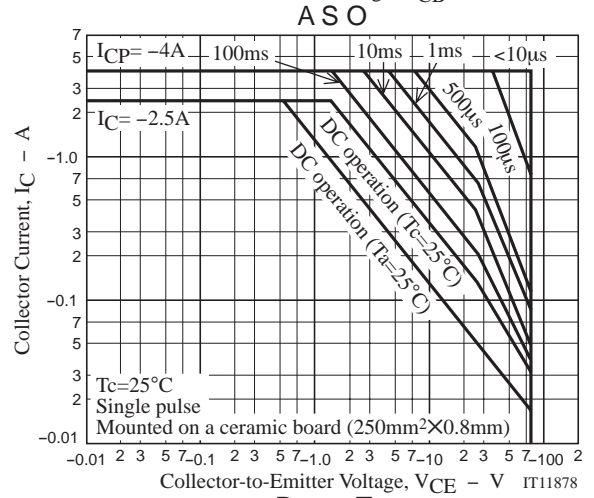
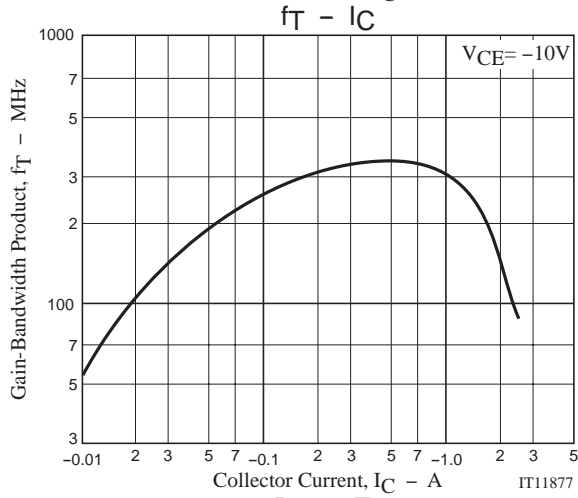
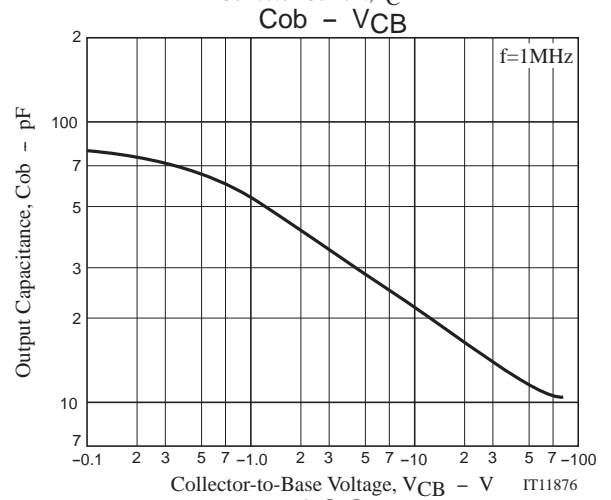
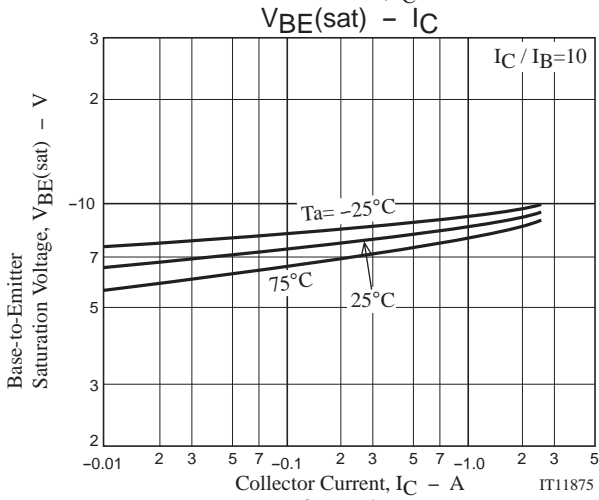
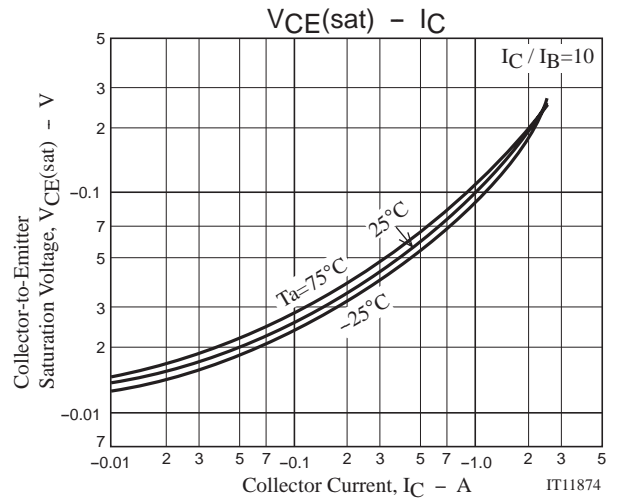
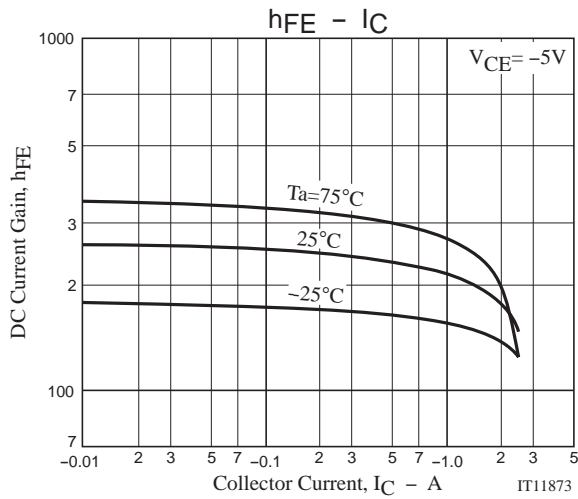
unit : mm (typ)

7007A-004



## Switching Time Test Circuit





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